

**‘CALCULATED’ REFERENCE PATTERNS &
‘MEASURED’ REFERENCE SCANS:
NEW DATABASE POSSIBILITIES**

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For many years the number of reference patterns calculated from atomic structure data is growing rapidly and actually exceeding the number of experimental patterns. Since the release of the ICDD PDF4+ 2009 product also full profiles a.k.a. measured scans are stored in this database. The number of reference patterns including these scans is growing too.

In this presentation we will demonstrate how measured scans included in a database (ICDD or user data) can be exploited as references for automatic classification analysis and are applied in production control. This feature will be implemented in a new version of the HighScore and HighScore Plus software. Furthermore we will compare match-scores from experimental and from calculated reference patterns.